

Notice of References Cited	Application/Control No. 10/661,612		Applicant(s)/Patent Under Reexamination COYNE ET AL.	
	Examiner Thuy N. Pardo		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0051210	03-2003	Collier et al.	715/507
*	C	US-2006/0168362	07-2006	Kaneko, Seiji	710/008
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*	E	US-7,346,754	03-2008	Kaneko, Seiji	711/170
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	V	Waiman Cheung et al., "The model-assisted global query system for multiple databases in distributed enterprises", ACM, 10/1996, pp. 421-470			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.